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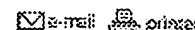
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 Lach, J.; Mangione-Smith, W.H.; Potkonjak, M.;
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 AbstractPlus Full Text: PDF(636 KB) IEEE CNF</p> |
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 Kitsos, P.; Sklavos, N.; Koufopavlou, O.;
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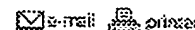
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Brosa, A.M.; Figueras, J.;
Test Conference, 2000. Proceedings. International
3-5 Oct. 2000 Page(s):1041 - 1050
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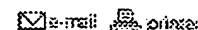
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- ☐ 1. **Adaptive nondisruptive measurement of harmonic distortion for voiceband data transmission**
Zervos, N.A.; Cupo, R.L.;
Communications, IEEE Transactions on
Volume 43, Issue 7, July 1995 Page(s):2184 - 2200
[AbstractPlus](#) | Full Text: [PDF](#)(1392 KB) IEEE JNL
- ☐ 2. **A 300-MHz 115-W 32-b bipolar ECL microprocessor**
Jouppi, N.P.; Boyle, P.; Dion, J.; Doherty, M.J.; Eustace, A.; Haddad, R.W.; Mayo, R.; Menon, S.
Monier, L.M.; Stark, D.; Turrini, S.; Yang, J.L.; Hamburg, R.; Fitch, J.S.; Kao, R.;
Solid-State Circuits, IEEE Journal of
Volume 28, Issue 11, Nov. 1993 Page(s):1152 - 1166
[AbstractPlus](#) | Full Text: [PDF](#)(1572 KB) IEEE JNL
- ☐ 3. **Switched-capacitor simulation models for full-chips verification**
Chanak, T.; Chadha, R.; Singhal, K.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on
Volume 11, Issue 11, Nov. 1992 Page(s):1363 - 1371
[AbstractPlus](#) | Full Text: [PDF](#)(788 KB) IEEE JNL
- ☐ 4. **Improved implementation of the silicon cochlea**
Watts, L.; Kerns, D.A.; Lyon, R.F.; Mead, C.A.;
Solid-State Circuits, IEEE Journal of
Volume 27, Issue 5, May 1992 Page(s):692 - 700
[AbstractPlus](#) | Full Text: [PDF](#)(644 KB) IEEE JNL
- ☐ 5. **The 68040 processor. 2. Memory design and chip**
Edenfield, R.W.; Gallup, M.G.; Ledbetter, W.B., Jr.; McGarity, R.C.; Quintana, E.E.; Reininger, R.
Micro, IEEE
Volume 10, Issue 3, June 1990 Page(s):22 - 35
[AbstractPlus](#) | Full Text: [PDF](#)(1243 KB) IEEE JNL
- ☐ 6. **On-wafer verification of a large-signal MESFET model**
Curtice, W.R.; Pak, S.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 37, Issue 11, Nov. 1989 Page(s):1809 - 1811
[AbstractPlus](#) | Full Text: [PDF](#)(256 KB) IEEE JNL
- ☐ 7. **System-on-a-chip verification-methodology and techniques**
Ferrari, F.;

Circuits and Devices Magazine, IEEE
Volume 18, Issue 6, Nov. 2002 Page(s):39 - 39
[AbstractPlus](#) | Full Text: [PDF](#)(163 KB) IEEE JNL

- ☐ **8. NOISY: an electrical noise checker for ULSI**
Gourdy, F.; Greiner, A.; Guillemet, M.; Marbot, R.; Murzin, J.;
Computer-Aided Design, 1988. ICCAD-88. Digest of Technical Papers., IEEE International Conference on
7-10 Nov. 1988 Page(s):226 - 229
[AbstractPlus](#) | Full Text: [PDF](#)(160 KB) IEEE CNF
- ☐ **9. Switched-capacitor simulation models for full-chip verification**
Chanak, T.; Chadha, R.; Singhal, K.;
Custom Integrated Circuits Conference, 1989., Proceedings of the IEEE 1989
15-18 May 1989 Page(s):21.1/1 - 21.1/4
[AbstractPlus](#) | Full Text: [PDF](#)(280 KB) IEEE CNF
- ☐ **10. Built-in test methodology for a full custom processor chip**
Shergill, R.S.; Yeung, P.-H.; Tucci, P.A.;
Computer Design: VLSI in Computers and Processors, 1989. ICCD '89. Proceedings., 1989 IEEE International Conference on
2-4 Oct. 1989 Page(s):571 - 575
[AbstractPlus](#) | Full Text: [PDF](#)(408 KB) IEEE CNF
- ☐ **11. Integrated programmable operational amplifiers with improved characteristics**
Michael, S.; Cristi, R.;
Euro ASIC '90
29 May-1 June 1990 Page(s):74 - 79
[AbstractPlus](#) | Full Text: [PDF](#)(352 KB) IEEE CNF
- ☐ **12. The design and verification of a VLSI chip for electrocardiogram data compression**
Roy, S.C.; Krakow, W.T.; Sacks, B.; Batchelor, W.E.; Bohs, L.N.; Barr, R.C.;
Computer-Based Medical Systems, 1990., Proceedings of Third Annual IEEE Symposium on
3-6 June 1990 Page(s):170 - 177
[AbstractPlus](#) | Full Text: [PDF](#)(500 KB) IEEE CNF
- ☐ **13. Linearity, accuracy and bandwidth considerations in wideband CMOS voltage amplifiers**
Ramirez-Angulo, J.; Sadkowski, R.; Sanchez-Sinencio, E.;
Circuits and Systems, 1993., ISCAS '93, 1993 IEEE International Symposium on
3-6 May 1993 Page(s):1251 - 1254 vol.2
[AbstractPlus](#) | Full Text: [PDF](#)(196 KB) IEEE CNF
- ☐ **14. Design of a high complexity superscalar microprocessor with the portable IDPS ASIC library**
Greiner, A.; Lucas, L.; Wajsburt, F.; Winckel, L.;
European Design and Test Conference, 1994. EDAC, The European Conference on Design Automation
ETC European Test Conference. EUROASIC, The European Event in ASIC Design, Proceedings
28 Feb.-3 March 1994 Page(s):9 - 13
[AbstractPlus](#) | Full Text: [PDF](#)(416 KB) IEEE CNF
- ☐ **15. Stray insensitive implementation of programmable switched capacitor amplifiers**
Michael, S.;
Circuits and Systems, 1994. ISCAS '94., 1994 IEEE International Symposium on
Volume 5, 30 May-2 June 1994 Page(s):577 - 580 vol.5
[AbstractPlus](#) | Full Text: [PDF](#)(280 KB) IEEE CNF
- ☐ **16. An efficient subcircuit extraction algorithm by resource management**
Zong Ling; Yun, D.Y.Y.;
ASIC, 1996. 2nd International Conference on
21-24 Oct. 1996 Page(s):9 - 14
[AbstractPlus](#) | Full Text: [PDF](#)(548 KB) IEEE CNF

- ☐ **17. Optical probing of internal signals in silicon ICs**
De Venuto, D.; Corsi, F.; Breglio, G.; Cutolo, A.; Zeni, L.;
Electrotechnical Conference, 1996. MELECON '96., 8th Mediterranean
Volume 1, 13-16 May 1996 Page(s):377 - 380 vol.1
[AbstractPlus](#) | Full Text: [PDF\(332 KB\)](#) IEEE CNF
- ☐ **18. Use of a laser beam probe for the non-invasive measurement of signals in silicon ICs**
De Venuto, D.; Corsi, F.;
Instrumentation and Measurement Technology Conference, 1996. IMTC-96. Conference Proceed-
'Quality Measurements: The Indispensable Bridge between Theory and Reality', IEEE
Volume 2, 1996 Page(s):1050 - 1055 vol.2
[AbstractPlus](#) | Full Text: [PDF\(440 KB\)](#) IEEE CNF
- ☐ **19. On the complexity of bridging fault simulation techniques for CMOS integrated circuits**
Ryan, C.A.;
ASIC Conference and Exhibit, 1995., Proceedings of the Eighth Annual IEEE International
18-22 Sept. 1995 Page(s):160 - 163
[AbstractPlus](#) | Full Text: [PDF\(484 KB\)](#) IEEE CNF
- ☐ **20. Bridging fault simulation using Iddq, logic, and delay testing**
Ryan, C.A.;
AUTOTESTCON '95. 'Systems Readiness: Test Technology for the 21st Century'. Conference R
8-10 Aug. 1995 Page(s):176 - 180
[AbstractPlus](#) | Full Text: [PDF\(544 KB\)](#) IEEE CNF
- ☐ **21. The results of the VLSI implementation of high performance switched-capacitor analog bu
blocks**
Michael, S.;
Circuits and Systems, 1995., Proceedings., Proceedings of the 38th Midwest Symposium on
Volume 1, 13-16 Aug. 1995 Page(s):182 - 185 vol.1
[AbstractPlus](#) | Full Text: [PDF\(320 KB\)](#) IEEE CNF
- ☐ **22. SUBTRACT: a program for the efficient evaluation of substrate parasitics in integrated cir**
Verghese, N.K.; Allstot, D.J.;
Computer-Aided Design, 1995. ICCAD-95. Digest of Technical Papers., 1995 IEEE/ACM Interna
Conference on
5-9 Nov. 1995 Page(s):194 - 198
[AbstractPlus](#) | Full Text: [PDF\(444 KB\)](#) IEEE CNF
- ☐ **23. ECCOPUNCH: the Edinburgh classical conditioning pulsed neural chip**
Lehmann, T.;
Circuits and Systems, 1997. ISCAS '97., Proceedings of 1997 IEEE International Symposium on
Volume 1, 9-12 June 1997 Page(s):33 - 36 vol.1
[AbstractPlus](#) | Full Text: [PDF\(408 KB\)](#) IEEE CNF
- ☐ **24. A symbolic simulation-based ANSI/IEEE Std 1149.1 compliance checker and BSDL genera**
Singh, H.; Patankar, G.; Beausang, J.;
Test Conference, 1997. Proceedings., International
1-6 Nov. 1997 Page(s):256 - 264
[AbstractPlus](#) | Full Text: [PDF\(600 KB\)](#) IEEE CNF
- ☐ **25. Design and application of ATM-SDH multiplex/demultiplex ASIC**
Zhi Jun; Wei Shaojun; Chen Hongyi;
Communication Technology Proceedings, 1998. ICCT '98. 1998 International Conference on
22-24 Oct. 1998 Page(s):27 - 31 vol.1
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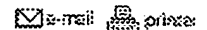
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Scholl, C.; Becker, B.; Weis, T.M.;
Computer-Aided Design, 1998. ICCAD 98. Digest of Technical Papers. 1998 IEEE/ACM International Conference on
8-12 Nov. 1998 Page(s):672 - 677
[AbstractPlus](#) | Full Text: [PDF\(572 KB\)](#) IEEE CNF
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Saleh, R.; Overhauser, D.; Taylor, S.;
Computer-Aided Design, 1998. ICCAD 98. Digest of Technical Papers. 1998 IEEE/ACM International Conference on
8-12 Nov. 1998 Page(s):453 - 460
[AbstractPlus](#) | Full Text: [PDF\(964 KB\)](#) IEEE CNF
- ☐ **28. Full-chip verification methods for DSM power distribution systems**
Steele, G.; Overhauser, D.; Rochel, S.; Hussain, S.Z.;
Design Automation Conference, 1998. Proceedings
15-19 June 1998 Page(s):744 - 749
[AbstractPlus](#) | Full Text: [PDF\(1072 KB\)](#) IEEE CNF
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Ribarich, T.J.; Ribarich, J.J.;
Industry Applications Conference, 1998. Thirty-Third IAS Annual Meeting. The 1998 IEEE Volume 3, 12-15 Oct. 1998 Page(s):2038 - 2043 vol.3
[AbstractPlus](#) | Full Text: [PDF\(388 KB\)](#) IEEE CNF
- ☐ **30. A system-level co-verification environment for ATM hardware design**
Post, G.; Muller, A.; Grotker, T.;
Design, Automation and Test in Europe, 1998., Proceedings
23-26 Feb. 1998 Page(s):424 - 428
[AbstractPlus](#) | Full Text: [PDF\(52 KB\)](#) IEEE CNF
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Xian-Quan Zhang; Tsang, T.; Mehta, D.;
Electrical and Computer Engineering, 1999 IEEE Canadian Conference on
Volume 1, 9-12 May 1999 Page(s):538 - 542 vol.1
[AbstractPlus](#) | Full Text: [PDF\(496 KB\)](#) IEEE CNF

32. A new control IC for dimmable high-frequency electronic ballasts

- ☐ Adams, J.; Ribarich, T.J.; Ribarich, J.J.;
Applied Power Electronics Conference and Exposition, 1999. APEC '99. Fourteenth Annual
Volume 2, 14-18 March 1999 Page(s):713 - 719 vol.2
[AbstractPlus](#) | Full Text: [PDF](#)(440 KB) IEEE CNF
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Johansson, J.;
Ultrasonics Symposium, 2000 IEEE
Volume 2, 22-25 Oct. 2000 Page(s):1049 - 1054 vol.2
[AbstractPlus](#) | Full Text: [PDF](#)(388 KB) IEEE CNF
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transconductance multipliers**
Ramirez-Angulo, J.; Choi, S.C.; Zrilic, J.Z.;
Circuits and Systems, 2000. Proceedings. ISCAS 2000 Geneva. The 2000 IEEE International
Symposium on
Volume 5, 28-31 May 2000 Page(s):381 - 384 vol.5
[AbstractPlus](#) | Full Text: [PDF](#)(312 KB) IEEE CNF
- ☐ **35. A hardware and software monitor for high-level system-on-chip verification**
El Shobaki, M.; Lindh, L.;
Quality Electronic Design, 2001 International Symposium on
26-28 March 2001 Page(s):56 - 61
[AbstractPlus](#) | Full Text: [PDF](#)(582 KB) IEEE CNF
- ☐ **36. Simulation of on-chip interconnection effects in CMOS circuits**
Piwowarska, E.;
CAD Systems in Microelectronics, 2001. CADSM 2001. Proceedings of the 6th International
Conference. The Experience of Designing and Application of
12-17 Feb. 2001 Page(s):246 - 249
[AbstractPlus](#) | Full Text: [PDF](#)(303 KB) IEEE CNF
- ☐ **37. The RF interface circuits design of contactless IC cards**
Lu Chao; Li Yong-ming;
ASIC, 2001. Proceedings. 4th International Conference on
23-25 Oct. 2001 Page(s):278 - 280
[AbstractPlus](#) | Full Text: [PDF](#)(265 KB) IEEE CNF
- ☐ **38. GSTE through a case study [digital IC verification]**
Yang, J.; Goel, A.;
Computer Aided Design, 2002. ICCAD 2002. IEEE/ACM International Conference on
10-14 Nov. 2002 Page(s):534 - 541
[AbstractPlus](#) | Full Text: [PDF](#)(592 KB) IEEE CNF
- ☐ **39. VeriCDF: a new verification methodology for charged device failures**
Jaesik Lee; Ki-Wook Kim; Sung-Mo Kang;
Design Automation Conference, 2002. Proceedings. 39th
10-14 June 2002 Page(s):874 - 879
[AbstractPlus](#) | Full Text: [PDF](#)(697 KB) IEEE CNF
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interleaving delta modulation**
Nagle, P.J.; Burton, D.P.; Heaney, E.P.; McGrath, F.J.;
Solid-State Circuits Conference, 2002. Digest of Technical Papers. ISSCC. 2002 IEEE Internatio
Volume 1, 3-7 Feb. 2002 Page(s):296 - 467 vol.1
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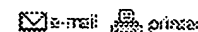
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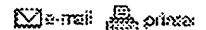
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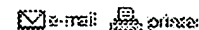
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 Information Theory, IEEE Transactions on
 Volume 42, Issue 2, March 1996 Page(s):566 - 578
 AbstractPlus References Full Text: PDF(1084 KB) IEEE JNL</p> |
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 Volume 28, Issue 1, Jan. 1995 Page(s):50 - 54
 AbstractPlus References Full Text: PDF(472 KB) IEEE JNL</p> |
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 AbstractPlus Full Text: PDF(628 KB) IEEE JNL</p> |
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 Chowdhury, D.R.; Gupta, I.S.; Chaudhuri, P.P.;
 Computers, IEEE Transactions on
 Volume 44, Issue 10, Oct. 1995 Page(s):1260 - 1264
 AbstractPlus References Full Text: PDF(424 KB) IEEE JNL</p> |
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 Ganguly, S.; Silberschatz, A.; Tsur, S.;
 Knowledge and Data Engineering, IEEE Transactions on
 Volume 7, Issue 3, June 1995 Page(s):351 - 361
 AbstractPlus References Full Text: PDF(980 KB) IEEE JNL</p> |
| <input type="checkbox"/> | <p>6. Using tries to eliminate pattern collisions in perfect hashing
 Brain, M.D.; Sharp, A.L.;
 Knowledge and Data Engineering, IEEE Transactions on
 Volume 6, Issue 2, April 1994 Page(s):239 - 247
 AbstractPlus Full Text: PDF(868 KB) IEEE JNL</p> |
| <input type="checkbox"/> | <p>7. Immunizing public key cryptosystems against chosen ciphertext attacks
 Zheng, Y.; Seberry, J.;
 Selected Areas in Communications, IEEE Journal on</p> |

Volume 11, Issue 5, June 1993 Page(s):715 - 724

[AbstractPlus](#) | Full Text: [PDF](#)(976 KB) IEEE JNL

- ☐ **8. A survey of encryption standards**
Kaliski, B.;
Micro, IEEE
Volume 13, Issue 6, Dec. 1993 Page(s):74 - 81
[AbstractPlus](#) | Full Text: [PDF](#)(664 KB) IEEE JNL

- ☐ **9. A comparison of hashing schemes for address lookup in computer networks**
Jain, R.;
Communications, IEEE Transactions on
Volume 40, Issue 10, Oct. 1992 Page(s):1570 - 1573
[AbstractPlus](#) | Full Text: [PDF](#)(276 KB) IEEE JNL

- ☐ **10. A simple mechanism for type security across compilation units**
Scott, M.L.; Finkel, R.A.;
Software Engineering, IEEE Transactions on
Volume 14, Issue 8, Aug. 1988 Page(s):1238 - 1239
[AbstractPlus](#) | Full Text: [PDF](#)(200 KB) IEEE JNL

- ☐ **11. Hashing for dynamic and static internal tables**
Lewis, T.G.; Cook, C.R.;
Computer
Volume 21, Issue 10, Oct. 1988 Page(s):45 - 56
[AbstractPlus](#) | Full Text: [PDF](#)(968 KB) IEEE JNL

- ☐ **12. Construction of secure and fast hash functions using nonbinary error-correcting codes**
Knudsen, L.; Preneel, B.;
Information Theory, IEEE Transactions on
Volume 48, Issue 9, Sept. 2002 Page(s):2524 - 2539
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(456 KB) IEEE JNL

- ☐ **13. Securing XML documents with Author-X**
Bertino, E.; Castano, S.; Ferrari, E.;
Internet Computing, IEEE
Volume 5, Issue 3, May-June 2001 Page(s):21 - 31
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(524 KB) IEEE JNL

- ☐ **14. Trajectory sampling for direct traffic observation**
Duffield, N.G.; Grossglauser, M.;
Networking, IEEE/ACM Transactions on
Volume 9, Issue 3, June 2001 Page(s):280 - 292
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(252 KB) IEEE JNL

- ☐ **15. An improved hashing function for IS-2000 quick paging channel**
Munje, A.; Islam, M.K.;
Communications Letters, IEEE
Volume 5, Issue 1, Jan. 2001 Page(s):7 - 9
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(92 KB) IEEE JNL

- ☐ **16. Fault resilient and compression tolerant digital signature for image authentication**
Der-Chyuan Lou; Jiang-Lung Liu;
Consumer Electronics, IEEE Transactions on
Volume 46, Issue 1, Feb. 2000 Page(s):31 - 39
[AbstractPlus](#) | Full Text: [PDF](#)(276 KB) IEEE JNL

- ☐ **17. An attack on the Hwang-Chang-Hwang watermarking scheme**
Chi-Kwong Chan; Cheng, L.M.;
Consumer Electronics, IEEE Transactions on

Volume 46, Issue 1, Feb. 2000 Page(s):40 - 43

[AbstractPlus](#) | [Full Text: PDF\(212 KB\)](#) IEEE JNL

- ☐ **18. Formal characterization and automated analysis of known-pair and chosen-text attacks**
Stubblebine, S.G.; Meadows, C.A.;
Selected Areas in Communications, IEEE Journal on
Volume 18, Issue 4, April 2000 Page(s):571 - 581
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(136 KB\)](#) IEEE JNL

- ☐ **19. Strongly universal hashing and identification codes via channels**
Kurosawa, K.; Yoshida, T.;
Information Theory, IEEE Transactions on
Volume 45, Issue 6, Sept. 1999 Page(s):2091 - 2095
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(164 KB\)](#) IEEE JNL

- ☐ **20. A watermarking technique based on one-way hash functions**
Min-Shiang Hwang; Chin-Chen Chang; Kuo-Feng Hwang;
Consumer Electronics, IEEE Transactions on
Volume 45, Issue 2, May 1999 Page(s):286 - 294
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(888 KB\)](#) IEEE JNL

- ☐ **21. On the security of iterated message authentication codes**
Preneel, B.; van Oorschot, P.C.;
Information Theory, IEEE Transactions on
Volume 45, Issue 1, Jan. 1999 Page(s):188 - 199
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(332 KB\)](#) IEEE JNL

- ☐ **22. Reducing the storage requirements of a perfect hash function**
Di Felice, P.; Madama, U.;
Knowledge and Data Engineering, IEEE Transactions on
Volume 10, Issue 6, Nov.-Dec. 1998 Page(s):1005 - 1007
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(236 KB\)](#) IEEE JNL

- ☐ **23. Managing statistical behavior of large data sets in shared-nothing architectures**
Rigoutsos, I.; Delis, A.;
Parallel and Distributed Systems, IEEE Transactions on
Volume 9, Issue 11, Nov. 1998 Page(s):1073 - 1087
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(320 KB\)](#) IEEE JNL

- ☐ **24. Key distribution for secure VSAT satellite communications**
Jeong-Hyun Park; Sun-Bae Lim;
Broadcasting, IEEE Transactions on
Volume 44, Issue 3, Sept. 1998 Page(s):274 - 277
[AbstractPlus](#) | [Full Text: PDF\(324 KB\)](#) IEEE JNL

- ☐ **25. Using self-organizing maps to learn geometric hash functions for model-based object recognition**
Bebis, G.; Georgiopoulos, M.; Lobo, N.V.;
Neural Networks, IEEE Transactions on
Volume 9, Issue 3, May 1998 Page(s):560 - 570
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(372 KB\)](#) IEEE JNL

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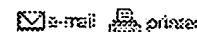
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|--------------------------|--|
| <input type="checkbox"/> | 26. Scalable global and local hashing strategies for duplicate pruning in parallel A* graph sea
Mahapatra, N.R.; Dutt, S.;
Parallel and Distributed Systems, IEEE Transactions on
Volume 8, Issue 7, July 1997 Page(s):738 - 756
AbstractPlus References Full Text: PDF (616 KB) IEEE JNL |
| <input type="checkbox"/> | 27. Phone number portability for PCS systems with ATM backbones using distributed dynami hashing
Ravi Jain; Rajagopalan, S.; Li Fung Chang;
Selected Areas in Communications, IEEE Journal on
Volume 15, Issue 1, Jan. 1997 Page(s):96 - 105
AbstractPlus References Full Text: PDF (400 KB) IEEE JNL |
| <input type="checkbox"/> | 28. Efficient hardware hashing functions for high performance computers
Ramakrishna; M.V.; Fu, E.; Bahcekapili, E.;
Computers, IEEE Transactions on
Volume 46, Issue 12, Dec. 1997 Page(s):1378 - 1381
AbstractPlus References Full Text: PDF (32 KB) IEEE JNL |
| <input type="checkbox"/> | 29. Authenticated key agreement without using one-way hash functions
Harn, L.; Lin, H.-Y.;
Electronics Letters
Volume 37, Issue 10, 10 May 2001 Page(s):629 - 630
AbstractPlus Full Text: PDF (312 KB) IEE JNL |
| <input type="checkbox"/> | 30. Cryptanalysis of reduced version of HAVAL
Kasselmann, P.R.; Penzhorn, W.T.;
Electronics Letters
Volume 36, Issue 1, 6 Jan. 2000 Page(s):30 - 31
AbstractPlus Full Text: PDF (120 KB) IEE JNL |
| <input type="checkbox"/> | 31. Integrated approach for fault tolerance and digital signature in RSA
Zhang, C.N.;
Computers and Digital Techniques, IEE Proceedings-
Volume 146, Issue 3, May 1999 Page(s):151 - 159
AbstractPlus Full Text: PDF (360 KB) IEE JNL |
| <input type="checkbox"/> | 32. Linear approximation of integer additions
Sangwoo Park; Seongtaek Chee; Soo Hak Sung; |

Electronics Letters
Volume 35, Issue 24, 25 Nov. 1999 Page(s):2105 - 2106
[AbstractPlus](#) | Full Text: [PDF](#)(144 KB) IEE JNL

- ☐ **33. Authenticated key exchange protocols resistant to password guessing attacks**
Kwon, T.; Song, J.;
Communications, IEE Proceedings-
Volume 145, Issue 5, Oct. 1998 Page(s):304 - 308
[AbstractPlus](#) | Full Text: [PDF](#)(516 KB) IEE JNL
- ☐ **34. Analysis of hash function of Yi and Lam**
Martin, K.; Mitchell, C.J.;
Electronics Letters
Volume 34, Issue 24, 26 Nov. 1998 Page(s):2327 - 2328
[AbstractPlus](#) | Full Text: [PDF](#)(288 KB) IEE JNL
- ☐ **35. Signature scheme based on discrete logarithm without using one-way hash-function**
Yeun, C.Y.; Mitchell, C.J.; Ng, S.L.;
Electronics Letters
Volume 34, Issue 24, 26 Nov. 1998 Page(s):2329 - 2330
[AbstractPlus](#) | Full Text: [PDF](#)(236 KB) IEE JNL
- ☐ **36. Signature scheme based on discrete logarithm without using one-way hash function**
Zuhua Shao;
Electronics Letters
Volume 34, Issue 11, 28 May 1998 Page(s):1079 - 1080
[AbstractPlus](#) | Full Text: [PDF](#)(248 KB) IEE JNL
- ☐ **37. Conference key distribution system with user anonymity based on algebraic approach**
Wu, T.-C.;
Computers and Digital Techniques, IEE Proceedings-
Volume 144, Issue 2, March 1997 Page(s):145 - 148
[AbstractPlus](#) | Full Text: [PDF](#)(388 KB) IEE JNL
- ☐ **38. Hash function based on block cipher**
Xun Yi; Kwok Yan Lam;
Electronics Letters
Volume 33, Issue 23, 6 Nov. 1997 Page(s):1938 - 1940
[AbstractPlus](#) | Full Text: [PDF](#)(380 KB) IEE JNL
- ☐ **39. Cheating detection and cheater identification in secret sharing schemes**
Wu, T.-C.; Wu, T.-S.;
Computers and Digital Techniques, IEE Proceedings-
Volume 142, Issue 5, Sept. 1995 Page(s):367 - 369
[AbstractPlus](#) | Full Text: [PDF](#)(180 KB) IEE JNL
- ☐ **40. New digital signature scheme based on discrete logarithm**
Nyberg, K.;
Electronics Letters
Volume 30, Issue 6, 17 March 1994 Page(s):481
[AbstractPlus](#) | Full Text: [PDF](#)(176 KB) IEE JNL
- ☐ **41. Fortifying key negotiation schemes with poorly chosen passwords**
Anderson, R.J.; Lomas, T.M.A.;
Electronics Letters
Volume 30, Issue 13, 23 June 1994 Page(s):1040 - 1041
[AbstractPlus](#) | Full Text: [PDF](#)(184 KB) IEE JNL
- ☐ **42. Discrete logarithm hash function that is collision free and one way**
Gibson, J.K.;

Computers and Digital Techniques, IEE Proceedings E [see also Computers and Digital Techniq
IEE Proceedings-]

Volume 138, Issue 6, Nov. 1991 Page(s):407 - 410

[AbstractPlus](#) | Full Text: [PDF\(284 KB\)](#) IEE JNL

- ☐ **43. Some comments on Damgard's hashing principle**
Gibson, J.K.;
Electronics Letters
Volume 26, Issue 15, 19 July 1990 Page(s):1178 - 1179
[AbstractPlus](#) | Full Text: [PDF\(164 KB\)](#) IEE JNL

- ☐ **44. Sessions: source coding**
Information Theory, 1988. Abstracts of Papers., 1988 IEEE International Symposium on
19-24 June 1988 Page(s):138 - 140, 154-7, 179-81
[AbstractPlus](#) | Full Text: [PDF\(152 KB\)](#) IEEE CNF

- ☐ **45. Session: complexity**
Information Theory, 1988. Abstracts of Papers., 1988 IEEE International Symposium on
19-24 June 1988 Page(s):240 - 241
[AbstractPlus](#) | Full Text: [PDF\(96 KB\)](#) IEEE CNF

- ☐ **46. On universal classes of fast high performance hash functions, their time-space tradeoff, a
their applications**
Siegel, A.;
Foundations of Computer Science, 1989., 30th Annual Symposium on
30 Oct.-1 Nov. 1989 Page(s):20 - 25
[AbstractPlus](#) | Full Text: [PDF\(440 KB\)](#) IEEE CNF

- ☐ **47. Efficient cryptographic schemes provably as secure as subset sum**
Impagliazzo, R.; Naor, M.;
Foundations of Computer Science, 1989., 30th Annual Symposium on
30 Oct.-1 Nov. 1989 Page(s):236 - 241
[AbstractPlus](#) | Full Text: [PDF\(448 KB\)](#) IEEE CNF

- ☐ **48. Fault tolerant hashing and information retrieval using back propagation**
Dontas, K.; Sarma, J.; Srinivasan, P.; Wechsler, H.;
System Sciences, 1990., Proceedings of the Twenty-Third Annual Hawaii International Conferen
Volume iv, 2-5 Jan. 1990 Page(s):345 - 352 vol.4
[AbstractPlus](#) | Full Text: [PDF\(548 KB\)](#) IEEE CNF

- ☐ **49. Communication-space tradeoffs for unrestricted protocols**
Beame, P.; Tompa, M.; Yan, P.;
Foundations of Computer Science, 1990. Proceedings., 31st Annual Symposium on
22-24 Oct. 1990 Page(s):420 - 428 vol.1
[AbstractPlus](#) | Full Text: [PDF\(676 KB\)](#) IEEE CNF

- ☐ **50. On randomly interleaved memories**
Raghavan, R.; Hayes, J.P.;
Supercomputing '90. Proceedings of
12-16 Nov. 1990 Page(s):49 - 58
[AbstractPlus](#) | Full Text: [PDF\(664 KB\)](#) IEEE CNF

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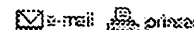
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Databases in Parallel and Distributed Systems, 1990, Proceedings. Second International Sympo
2-4 July 1990 Page(s):80 - 89
[AbstractPlus](#) | Full Text: [PDF](#)(828 KB) IEEE CNF
- ☐ **52. Perfect hashing, graph entropy, and circuit complexity**
Newman, I.; Ragde, P.; Wigderson, A.;
Structure in Complexity Theory Conference, 1990, Proceedings., Fifth Annual
8-11 July 1990 Page(s):91 - 99
[AbstractPlus](#) | Full Text: [PDF](#)(604 KB) IEEE CNF
- ☐ **53. The computational complexity of universal hashing**
Mansour, Y.; Nisan, N.; Tiwari, P.;
Structure in Complexity Theory Conference, 1990, Proceedings., Fifth Annual
8-11 July 1990 Page(s):90
[AbstractPlus](#) | Full Text: [PDF](#)(52 KB) IEEE CNF
- ☐ **54. Can Polynomials Be Good Hash Functions?**
Tillich, J.P.;
Information Theory, 1991 (papers in summary form only received), Proceedings. 1991 IEEE
International Symposium on (Cat. No.91CH3003-1)
24-28 June 1991 Page(s):128 - 128
[AbstractPlus](#) | Full Text: [PDF](#)(80 KB) IEEE CNF
- ☐ **55. Performance study of shift-folding skewing schemes for interleaved memory systems**
Guthy, B.S.;
Circuits and Systems, 1991., IEEE International Symposium on
11-14 June 1991 Page(s):2324 - 2327 vol.4
[AbstractPlus](#) | Full Text: [PDF](#)(268 KB) IEEE CNF
- ☐ **56. Data compression in view of data sealing**
Koch, E.; Sommer, M.;
Data Compression Conference, 1991. DCC '91.
8-11 April 1991 Page(s):427
[AbstractPlus](#) | Full Text: [PDF](#)(72 KB) IEEE CNF
- ☐ **57. Execution of regular DO loops on asynchronous multiprocessors**
Pei Ouyang;

Parallel Processing Symposium, 1991. Proceedings., Fifth International
30 April-2 May 1991 Page(s):605 - 610

[AbstractPlus](#) | Full Text: [PDF\(440 KB\)](#) IEEE CNF

- ☐ **58. Perfect hashing functions for hardware applications**
Ramakrishna, M.V.; Portice, G.A.;
Data Engineering, 1991. Proceedings. Seventh International Conference on
8-12 April 1991 Page(s):464 - 470
[AbstractPlus](#) | Full Text: [PDF\(444 KB\)](#) IEEE CNF
- ☐ **59. Protecting security information in distributed systems**
Fritzner, C.; Nilsen, L.; Skomedal, A.;
Research in Security and Privacy, 1991. Proceedings., 1991 IEEE Computer Society Symposium
20-22 May 1991 Page(s):245 - 254
[AbstractPlus](#) | Full Text: [PDF\(720 KB\)](#) IEEE CNF
- ☐ **60. Message authentication with one-way hash functions**
Tsudik, G.;
INFOCOM '92. Eleventh Annual Joint Conference of the IEEE Computer and Communications
Societies. IEEE
4-8 May 1992 Page(s):2055 - 2059 vol.3
[AbstractPlus](#) | Full Text: [PDF\(364 KB\)](#) IEEE CNF
- ☐ **61. Fault tolerant graphs, perfect hash functions and disjoint paths**
Ajtai, M.; Alon, N.; Bruck, J.; Cypher, R.; Ho, C.T.; Naor, M.; Szemeredi, E.;
Foundations of Computer Science, 1992. Proceedings., 33rd Annual Symposium on
24-27 Oct. 1992 Page(s):693 - 702
[AbstractPlus](#) | Full Text: [PDF\(688 KB\)](#) IEEE CNF
- ☐ **62. Tactical data management in a multilink translator and display system**
McNulty, J.M.;
Military Communications Conference, 1992. MILCOM '92, Conference Record. 'Communications
Fusing Command, Control and Intelligence', IEEE
11-14 Oct. 1992 Page(s):524 - 529 vol.2
[AbstractPlus](#) | Full Text: [PDF\(564 KB\)](#) IEEE CNF
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Wu, C.H.; Whitson, G.M.; Hsiao, C.-T.; Huang, C.-F.;
Supercomputing '92. Proceedings
16-20 Nov. 1992 Page(s):797 - 803
[AbstractPlus](#) | Full Text: [PDF\(472 KB\)](#) IEEE CNF
- ☐ **64. A simple perfect hashing method for static sets**
Ramakrishna, M.V.;
Computing and Information, 1992. Proceedings. ICCI '92., Fourth International Conference on
28-30 May 1992 Page(s):401 - 404
[AbstractPlus](#) | Full Text: [PDF\(304 KB\)](#) IEEE CNF
- ☐ **65. Hash-semijoin: a new technique for minimizing distributed query time**
Tung Shou Chen; Chen, A.L.P.; Wei-Pang Yang;
Distributed Computing Systems, 1992., Proceedings of the Third Workshop on Future Trends of
14-16 April 1992 Page(s):325 - 330
[AbstractPlus](#) | Full Text: [PDF\(412 KB\)](#) IEEE CNF
- ☐ **66. Hash functions for information authentication**
Preneel, B.; Govaerts, R.; Vandewalle, J.;
CompEuro '92. 'Computer Systems and Software Engineering', Proceedings.
4-8 May 1992 Page(s):475 - 480
[AbstractPlus](#) | Full Text: [PDF\(576 KB\)](#) IEEE CNF

- ☐ **67. Differential hashing functions: application to reachability graph generation**
Cousin, B.;
Computing and Information, 1993. Proceedings ICCI '93., Fifth International Conference on
27-29 May 1993 Page(s):190 - 194
[AbstractPlus](#) | Full Text: [PDF](#)(492 KB) IEEE CNF
- ☐ **68. Text searching on Splash 2**
Pryor, D.V.; Thistle, M.R.; Shirazi, N.;
FPGAs for Custom Computing Machines, 1993. Proceedings. IEEE Workshop on
5-7 April 1993 Page(s):172 - 177
[AbstractPlus](#) | Full Text: [PDF](#)(476 KB) IEEE CNF
- ☐ **69. Perfect hash functions made parallel-Lazy functional programming on a distributed multiprocessor**
Checkland, I.; Runciman, C.;
System Sciences, 1993, Proceeding of the Twenty-Sixth Hawaii International Conference on
Volume ii, 5-8 Jan. 1993 Page(s):397 - 406 vol.2
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- ☐ **70. Scalable duplicate pruning strategies for parallel A* graph search**
Mahapatra, N.R.; Dutt, S.;
Parallel and Distributed Processing, 1993. Proceedings of the Fifth IEEE Symposium on
1-4 Dec. 1993 Page(s):290 - 297
[AbstractPlus](#) | Full Text: [PDF](#)(784 KB) IEEE CNF
- ☐ **71. On virtual partitioning of large dictionaries for contextual post-processing to improve character recognition**
Hoch, R.; Kieninger, T.;
Document Analysis and Recognition, 1993., Proceedings of the Second International Conference
20-22 Oct. 1993 Page(s):226 - 231
[AbstractPlus](#) | Full Text: [PDF](#)(552 KB) IEEE CNF
- ☐ **72. Fast rehashing in PRAM emulations**
Keller, J.;
Parallel and Distributed Processing, 1993. Proceedings of the Fifth IEEE Symposium on
1-4 Dec. 1993 Page(s):626 - 631
[AbstractPlus](#) | Full Text: [PDF](#)(472 KB) IEEE CNF
- ☐ **73. Parallel implementation of the trie structure**
Chan, I.W.; Lim, C.Y.;
Parallel and Distributed Systems, 1994. International Conference on
19-21 Dec. 1994 Page(s):538 - 543
[AbstractPlus](#) | Full Text: [PDF](#)(480 KB) IEEE CNF
- ☐ **74. A study of cache hashing functions for symbolic applications in micro-parallel processor:**
Ching-Long Su; Chen-Chiu Teng; Despain, A.M.;
Parallel and Distributed Systems, 1994. International Conference on
19-21 Dec. 1994 Page(s):530 - 535
[AbstractPlus](#) | Full Text: [PDF](#)(556 KB) IEEE CNF
- ☐ **75. An introduction to the S SPIN hash function: making more out of the multidimensional array**
Coburn, T.K.;
Aerospace and Electronics Conference, 1994. NAECON 1994., Proceedings of the IEEE 1994 N
23-27 May 1994 Page(s):919 - 925 vol.2
[AbstractPlus](#) | Full Text: [PDF](#)(452 KB) IEEE CNF

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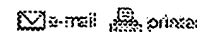




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 Wigderson, A.;
 Structure in Complexity Theory Conference, 1994., Proceedings of the Ninth Annual
 28 June-1 July 1994 Page(s):59 - 62
 AbstractPlus Full Text: PDF(228 KB) IEEE CNF</p> |
| <input type="checkbox"/> | <p>77. Occluded object recognition using extended local features and hashing
 Joong-Hwan Baek; Teague, K.A.;
 Systems, Man, and Cybernetics, 1994. 'Humans, Information and Technology', 1994 IEEE Inter
 Conference on
 Volume 3, 2-5 Oct. 1994 Page(s):2367 - 2372 vol.3
 AbstractPlus Full Text: PDF(356 KB) IEEE CNF</p> |
| <input type="checkbox"/> | <p>78. Ambiguity of integer sequences and application
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 Information Theory, 1994. Proceedings., 1994 IEEE International Symposium on
 27 June-1 July 1994 Page(s):369
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| <input type="checkbox"/> | <p>79. Hash based parallel algorithms for mining association rules
 Shintani, T.; Kitsuregawa, M.;
 Parallel and Distributed Information Systems, 1996., Fourth International Conference on
 18-20 Dec. 1996 Page(s):19 - 30
 AbstractPlus Full Text: PDF(1000 KB) IEEE CNF</p> |
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 Jain, R.; Rajagopalan, S.; Li-Fung Chang;
 Personal, Indoor and Mobile Radio Communications, 1996. PIMRC'96., Seventh IEEE Internatio
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 Volume 2, 15-18 Oct. 1996 Page(s):593 - 597 vol.2
 AbstractPlus Full Text: PDF(572 KB) IEEE CNF</p> |
| <input type="checkbox"/> | <p>81. Cryptographic security evaluation of MD4 hash function
 Abdel-Azeem, E.; Seireg, R.; Shaheen, S.I.;
 Radio Science Conference, 1996. NRSC '96., Thirteenth National
 19-21 March 1996 Page(s):345 - 354
 AbstractPlus Full Text: PDF(596 KB) IEEE CNF</p> |

82. Experiments on estimating random mapping

- ☐ Ho, K.M.; Wang, C.J.;
Neural Networks, 1996., IEEE International Conference on
Volume 1, 3-6 June 1996 Page(s):377 - 380 vol.1
[AbstractPlus](#) | Full Text: [PDF\(268 KB\)](#) IEEE CNF
- ☐ **83. A stable distributed tuple space**
Cannon, S.R.; Brinkerhof, D.A.;
System Sciences, 1996., Proceedings of the Twenty-Ninth Hawaii International Conference on ,
Volume 1, 3-6 Jan. 1996 Page(s):22 - 30 vol.1
[AbstractPlus](#) | Full Text: [PDF\(832 KB\)](#) IEEE CNF
- ☐ **84. A simple tree pattern matching algorithm for code generator**
Tzer-Shyong Chen; Feipei Lai; Rung-Ji Shang;
Computer Software and Applications Conference, 1995. COMPSAC 95. Proceedings., Nineteenth Annual International
9-11 Aug. 1995 Page(s):162 - 167
[AbstractPlus](#) | Full Text: [PDF\(420 KB\)](#) IEEE CNF
- ☐ **85. Authenticated key distribution and secure broadcast using no conventional encryption: a approach based on block codes**
Deng, R.H.; Li Gong; Lazar, A.A.; Weiguo Wang;
Global Telecommunications Conference, 1995. GLOBECOM '95., IEEE
Volume 2, 13-17 Nov. 1995 Page(s):1193 - 1197 vol.2
[AbstractPlus](#) | Full Text: [PDF\(500 KB\)](#) IEEE CNF
- ☐ **86. A hashing-based scheme for organizing vector quantization codebook**
Choo, C.Y.; Kristenson, E.; Nasrabadi, N.M.; Ran, X.;
Acoustics, Speech, and Signal Processing, 1995. ICASSP-95., 1995 International Conference on
Volume 4, 9-12 May 1995 Page(s):2495 - 2498 vol.4
[AbstractPlus](#) | Full Text: [PDF\(284 KB\)](#) IEEE CNF
- ☐ **87. Learning geometric hashing functions for model-based object recognition**
Bebis, G.; Georgiopoulos, M.; da Vitoria Lobo, N.;
Computer Vision, 1995. Proceedings., Fifth International Conference on
20-23 June 1995 Page(s):543 - 548
[AbstractPlus](#) | Full Text: [PDF\(580 KB\)](#) IEEE CNF
- ☐ **88. Stereoscopic families of permutations, and their applications**
Feige, U.; Krauthgamer, R.;
Theory of Computing and Systems, 1997., Proceedings of the Fifth Israeli Symposium on
17-19 June 1997 Page(s):85 - 95
[AbstractPlus](#) | Full Text: [PDF\(1048 KB\)](#) IEEE CNF
- ☐ **89. Word based multiple dictionary scheme for text compression with application to 2D bar codes**
Ng, K.S.; Cheng, L.M.;
Data Compression Conference, 1997. DCC '97. Proceedings
25-27 March 1997 Page(s):457
[AbstractPlus](#) | Full Text: [PDF\(44 KB\)](#) IEEE CNF
- ☐ **90. A model for estimating installed first costs of NGPN translation in PCS systems**
Jain, R.;
Communications, 1997. ICC 97 Montreal, 'Towards the Knowledge Millennium'. 1997 IEEE International Conference on
Volume 1, 8-12 June 1997 Page(s):386 - 390 vol.1
[AbstractPlus](#) | Full Text: [PDF\(468 KB\)](#) IEEE CNF
- ☐ **91. Fast authentication codes based on random polynomial residue classes**
Afanassiev, V.; Smeets, B.; Gehrmann, C.;
Information Theory. 1997. Proceedings., 1997 IEEE International Symposium on
29 June-4 July 1997 Page(s):175

[AbstractPlus](#) | Full Text: [PDF\(100 KB\)](#) IEEE CNF

- ☐ **92. Hash codes**
Bassalygo, L.A.; Burmester, M.; Dyachkov, A.; Kabatianski, G.;
Information Theory. 1997. Proceedings., 1997 IEEE International Symposium on
29 June-4 July 1997 Page(s):174
[AbstractPlus](#) | Full Text: [PDF\(100 KB\)](#) IEEE CNF
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Khachatryan, G.; Andreasyan, A.;
Compression and Complexity of Sequences 1997. Proceedings
11-13 June 1997 Page(s):390 - 397
[AbstractPlus](#) | Full Text: [PDF\(224 KB\)](#) IEEE CNF
- ☐ **94. A fast attack on the MD4 hash function**
Kasselman, P.R.;
Communications and Signal Processing, 1997. COMSIG '97., Proceedings of the 1997 South Afri
Symposium on
9-10 Sept. 1997 Page(s):147 - 150
[AbstractPlus](#) | Full Text: [PDF\(336 KB\)](#) IEEE CNF
- ☐ **95. The SHADE cipher: an efficient hash-function-based Feistel network**
Adams, C.;
Electrical and Computer Engineering, 1997. IEEE 1997 Canadian Conference on
Volume 1, 25-28 May 1997 Page(s):338 - 342 vol.1
[AbstractPlus](#) | Full Text: [PDF\(480 KB\)](#) IEEE CNF
- ☐ **96. Dynamic word based text compression**
Ng, K.S.; Cheng, L.M.; Wong, C.H.;
Document Analysis and Recognition, 1997., Proceedings of the Fourth International Conference
Volume 1, 18-20 Aug. 1997 Page(s):412 - 416 vol.1
[AbstractPlus](#) | Full Text: [PDF\(284 KB\)](#) IEEE CNF
- ☐ **97. A low cost searching device for an ATM adapter**
Glaise, R.J.; Munier, J.M.;
Computer Communications and Networks, 1997. Proceedings., Sixth International Conference o
22-25 Sept. 1997 Page(s):488 - 493
[AbstractPlus](#) | Full Text: [PDF\(548 KB\)](#) IEEE CNF
- ☐ **98. Identifying library functions in executable file using patterns**
Van Emmerik, M.;
Software Engineering Conference, 1998. Proceedings. 1998 Australian
9-13 Nov. 1998 Page(s):90 - 97
[AbstractPlus](#) | Full Text: [PDF\(132 KB\)](#) IEEE CNF
- ☐ **99. ID-based cryptographic schemes using a non-interactive public-key distribution system**
Yuh-Min Tseng; Jinn-Ke Jan;
Computer Security Applications Conference, 1998, Proceedings., 14th Annual
7-11 Dec. 1998 Page(s):237 - 243
[AbstractPlus](#) | Full Text: [PDF\(160 KB\)](#) IEEE CNF
- ☐ **100. Automatic synthesis of hashing function circuits using evolutionary techniques**
Damiani, E.; Tettamanzi, A.G.B.; Liberali, V.;
Integrated Circuit Design, 1998. Proceedings. XI Brazilian Symposium on
30 Sept.-3 Oct. 1998 Page(s):42 - 45
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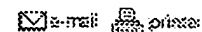
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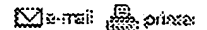


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Vielhauer, C.; Steinmetz, R.; Mayerhofer, A.;
Pattern Recognition, 2002. Proceedings. 16th International Conference on
Volume 1, 11-15 Aug. 2002 Page(s):123 - 126 vol.1

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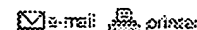
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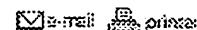




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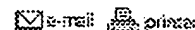




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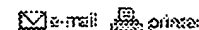
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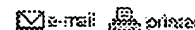


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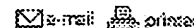
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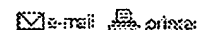
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Lee, T.C.; Tibel, D.; Sullivan, T.D.; Forhan, S.;
Reliability Physics Symposium, 2001. Proceedings. 39th Annual. 2001 IEEE International
30 April-3 May 2001 Page(s):172 - 183
[AbstractPlus](#) | Full Text: [PDF](#)(980 KB) IEEE CNF
- ☐ 2. **Production Implementation of a practical WLR program**
Garrard, S.;
Integrated Reliability Workshop, 1994. Final Report., 1994 International
16-19 Oct. 1994 Page(s):20 - 29
[AbstractPlus](#) | Full Text: [PDF](#)(648 KB) IEEE CNF
- ☐ 3. **Electromigration reliability indicators**
Jones, B.K.;
Semiconductor Processing - Quality through Measurement, IEE Colloquium on
27 Apr 1994 Page(s):3/1 - 310
[AbstractPlus](#) | Full Text: [PDF](#)(412 KB) IEE CNF
- ☐ 4. **On the life prediction and accelerated testing of solder joints**
Qian, Z.; Liu, S.;
Adhesive Joining and Coating Technology in Electronics Manufacturing, 1998. Proceedings of 3rd
International Conference on
28-30 Sept. 1998 Page(s):363
[AbstractPlus](#) | Full Text: [PDF](#)(36 KB) IEEE CNF
- ☐ 5. **Dynamic life-estimation of CMOS ICs in real operating environment: precise electrical met and MLE**
Kyung-Im Son; Soma, M.;
Reliability, IEEE Transactions on
Volume 46, Issue 1, March 1997 Page(s):31 - 37
[AbstractPlus](#) | Full Text: [PDF](#)(608 KB) IEEE JNL
- ☐ 6. **Experimental comparison of wafer level reliability (WLR) and packaged electromigration t**
Ryu, C.; Tse-Lun Tsai; Rogers, A.; Jesse, C.; Brozek, T.; Zarr, D.; Adamson, M.; Nayak, S.; Wall
Reliability Physics Symposium, 2001. Proceedings. 39th Annual. 2001 IEEE International
30 April-3 May 2001 Page(s):189 - 193
[AbstractPlus](#) | Full Text: [PDF](#)(564 KB) IEEE CNF
7. **Evaluation of test methods and associated test structures for interconnect reliability conti**

- ☐ Foley, S.; Molyneaux, J.; Mathewson, A.;
Microelectronic Test Structures, 1999. ICMTS 1999. Proceedings of the 1999 International Conference on
15-18 March 1999 Page(s):167 - 172
[AbstractPlus](#) | [Full Text: PDF\(552 KB\)](#) IEEE CNF
- ☐ 8. **Comparison of isothermal wafer-level EM and package-level EM for via test structure in dual damascene low k/Copper process**
Chang, M.N.; Chang, K.P.; Sue, K.C.;
Integrated Reliability Workshop Final Report, 2002. IEEE International
21-24 Oct. 2002 Page(s):192 - 195
[AbstractPlus](#) | [Full Text: PDF\(298 KB\)](#) IEEE CNF
- ☐ 9. **Assembly-level reliability: a methodology for effective manufacturing of IC packages**
Nguyen, L.T.; Finnell, J.R.; Singh, K.M.;
Reliability, IEEE Transactions on
Volume 44, Issue 1, March 1995 Page(s):14 - 18
[AbstractPlus](#) | [Full Text: PDF\(432 KB\)](#) IEEE JNL
- ☐ 10. **An evaluation of test methods for the detection and control of interconnect reliability**
Foley, S.; Molyneaux, J.; Mathewson, A.;
Semiconductor Manufacturing, IEEE Transactions on
Volume 13, Issue 2, May 2000 Page(s):127 - 135
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(220 KB\)](#) IEEE JNL
- ☐ 11. **TDDB on poly-gate single doping type capacitors**
Wang, S.-J.; Chen, I.-C.; Tigelaar, H.L.;
Reliability Physics Symposium 1992. 30th Annual Proceedings., International
31 March-2 April 1992 Page(s):54 - 57
[AbstractPlus](#) | [Full Text: PDF\(292 KB\)](#) IEEE CNF
- ☐ 12. **Building-in reliability, application to bipolar/CMOS/DMOS technology**
Gagnard, X.; Bonnaud, O.;
Physical and Failure Analysis of Integrated Circuits, 2002. IPFA 2002. Proceedings of the 9th
International Symposium on the
8-12 July 2002 Page(s):147 - 151
[AbstractPlus](#) | [Full Text: PDF\(800 KB\)](#) IEEE CNF
- ☐ 13. **The stability of laser weld interconnects in a-Si:H modules**
O'Dowd, J.G.; Johnson, B.J.; Oswald, R.S.; Willing, F.;
Photovoltaic Specialists Conference, 1993., Conference Record of the Twenty Third IEEE
10-14 May 1993 Page(s):926 - 929
[AbstractPlus](#) | [Full Text: PDF\(220 KB\)](#) IEEE CNF
- ☐ 14. **Impact of intermetal dielectric process on Al via electromigration reliability**
Liu, X.; Lo, K.F.; Chin, K.Y.; Guo, Q.; Teh, G.L.;
Physical and Failure Analysis of Integrated Circuits, 1999. Proceedings of the 1999 7th International
Symposium on the
5-9 July 1999 Page(s):60 - 63
[AbstractPlus](#) | [Full Text: PDF\(368 KB\)](#) IEEE CNF
- ☐ 15. **Soft errors induced by alpha particles**
Lantz, L., II;
Reliability, IEEE Transactions on
Volume 45, Issue 2, June 1996 Page(s):174 - 179
[AbstractPlus](#) | [References](#) | [Full Text: PDF\(596 KB\)](#) IEEE JNL
- ☐ 16. **Inner lead gang-bonded devices with stacked Ni-Au bumps**
Baggerman, A.F.J.; van Gerven, J.A.H.;
Components, Packaging, and Manufacturing Technology, Part B: Advanced Packaging, IEEE

Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transact Volume 18, Issue 2, May 1995 Page(s):366 - 374

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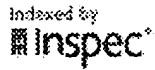
- ☐ **17. Fracture properties of molding compound materials for IC plastic packaging**
Sauber, J.; Lee, L.; Shih Hsu; Hongsmatip, T.;
Components, Packaging, and Manufacturing Technology, Part A, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on]
Volume 17, Issue 4, Dec. 1994 Page(s):533 - 541
[AbstractPlus](#) | Full Text: [PDF](#)(972 KB) IEEE JNL
- ☐ **18. Stress relief in plastic-encapsulated, integrated circuit devices by die coating with photodefinable polyimide**
Khan, M.M.; Tarter, T.S.; Fatemi, H.;
Electronics Components Conference, 1988., Proceedings of the 38th
9-11 May 1988 Page(s):425 - 431
[AbstractPlus](#) | Full Text: [PDF](#)(492 KB) IEEE CNF
- ☐ **19. Reliability testing of semiconductor devices in a humid environment**
Bazu, M.; Tazlauanu, M.;
Reliability and Maintainability Symposium, 1991. Proceedings., Annual
29-31 Jan. 1991 Page(s):307 - 311
[AbstractPlus](#) | Full Text: [PDF](#)(240 KB) IEEE CNF
- ☐ **20. Finite element analysis of a SWEAT structure with a 3-D, nonlinear, coupled thermal-elect model**
Dion, M.J.;
Reliability Physics Symposium 1992. 30th Annual Proceedings., International
31 March-2 April 1992 Page(s):232 - 238
[AbstractPlus](#) | Full Text: [PDF](#)(624 KB) IEEE CNF
- ☐ **21. Finite element analysis of a SWEAT structure with a 3-D, nonlinear, coupled thermal-elect model**
Dion, M.J.;
Microelectronic Test Structures, 1992. ICMTS 1992. Proceedings of the 1992 International Conference
16-19 March 1992 Page(s):12 - 17
[AbstractPlus](#) | Full Text: [PDF](#)(580 KB) IEEE CNF
- ☐ **22. Automated gated diode measurements for device characterization**
Verzi, B.; Aum, P.;
Microelectronic Test Structures, 1994. ICMTS 1994. Proceedings of the 1994 International Conference
22-25 March 1994 Page(s):141 - 146
[AbstractPlus](#) | Full Text: [PDF](#)(576 KB) IEEE CNF
- ☐ **23. Fracture properties of molding compound materials for IC plastic packaging**
Sauber, J.; Lee, L.; Hsu, S.; Hongsmatip, T.;
Electronic Components and Technology Conference, 1994. Proceedings., 44th
1-4 May 1994 Page(s):164 - 170
[AbstractPlus](#) | Full Text: [PDF](#)(804 KB) IEEE CNF
- ☐ **24. TAB Inner lead gang bonding on Ni-Au bumps**
Baggerman, A.F.J.; van Gerven, J.A.H.;
Electronic Components and Technology Conference, 1994. Proceedings., 44th
1-4 May 1994 Page(s):938 - 944
[AbstractPlus](#) | Full Text: [PDF](#)(692 KB) IEEE CNF
- ☐ **25. Simulation of electromigration damage in chip level interconnect lines: a grain structure based statistical approach**

Korhonen, M.A.; Korhonen, T.M.; Brown, D.D.; Li, C.-Y.;
Reliability Physics Symposium Proceedings, 1999. 37th Annual. 1999 IEEE International
23-25 March 1999 Page(s):227 - 232

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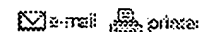
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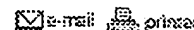
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 Nguyen, L.T.; Finnell, J.R.; Singh, K.M.;
 Reliability, IEEE Transactions on
 Volume 44, Issue 1, March 1995 Page(s):14 - 18
 AbstractPlus Full Text: PDF(432 KB) IEEE JNL</p> |
| <input type="checkbox"/> | <p>5. Inner lead gang-bonded devices with stacked Ni-Au bumps
 Baggerman, A.F.J.; van Gerven, J.A.H.;
 Components, Packaging, and Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transact
 Volume 18, Issue 2, May 1995 Page(s):366 - 374
 AbstractPlus Full Text: PDF(848 KB) IEEE JNL</p> |
| <input type="checkbox"/> | <p>6. TAB Inner lead gang bonding on Ni-Au bumps
 Baggerman, A.F.J.; van Gerven, J.A.H.;
 Electronic Components and Technology Conference, 1994. Proceedings., 44th
 1-4 May 1994 Page(s):938 - 944
 AbstractPlus Full Text: PDF(692 KB) IEEE CNF</p> |

- ☐ **7. Simulation of electromigration damage in chip level interconnect lines: a grain structure based statistical approach**
Korhonen, M.A.; Korhonen, T.M.; Brown, D.D.; Li, C.-Y.;
Reliability Physics Symposium Proceedings, 1999. 37th Annual. 1999 IEEE International
23-25 March 1999 Page(s):227 - 232
[AbstractPlus](#) | Full Text: [PDF\(452 KB\)](#) IEEE CNF

- ☐ **8. A study of formation and failure mechanism of CMP scratch induced defects on ILD in a W damascene interconnect SRAM cell**
Soon-Moon Jung; Jung-Sup Uom; Won-Suek Cho; Yong-Joon Bae; Yeon-Kyu Chung; Kwang-St Kil-Yeon Kim; Kyung-Tae Kim;
Reliability Physics Symposium, 2001. Proceedings. 39th Annual. 2001 IEEE International
30 April-3 May 2001 Page(s):42 - 47
[AbstractPlus](#) | Full Text: [PDF\(532 KB\)](#) IEEE CNF

- ☐ **9. Building-in reliability, application to bipolar/CMOS/DMOS technology**
Gagnard, X.; Bonnaud, O.;
Physical and Failure Analysis of Integrated Circuits, 2002. IPFA 2002. Proceedings of the 9th
International Symposium on the
8-12 July 2002 Page(s):147 - 151
[AbstractPlus](#) | Full Text: [PDF\(800 KB\)](#) IEEE CNF

- ☐ **10. Electromigration failure distribution of contacts and vias as a function of stress condition submicron IC metallizations**
Oates, A.S.;
Reliability Physics Symposium, 1996. 34th Annual Proceedings., IEEE International
30 April-2 May 1996 Page(s):164 - 171
[AbstractPlus](#) | Full Text: [PDF\(536 KB\)](#) IEEE CNF

- ☐ **11. A physics-of-failure (POF) approach to addressing device reliability in accelerated testing MCMs**
Evans, J.; Cushing, M.J.; Lall, P.; Bauernschub, R.;
Multi-Chip Module Conference, 1995. MCMC-95, Proceedings., 1995 IEEE
31 Jan.-2 Feb. 1995 Page(s):14 - 25
[AbstractPlus](#) | Full Text: [PDF\(808 KB\)](#) IEEE CNF

- ☐ **12. Method for equivalent acceleration of JEDEC/IPC moisture sensitivity levels**
Shook, R.L.; Vaccaro, B.T.; Gerlach, D.L.;
Reliability Physics Symposium Proceedings, 1998. 36th Annual. 1998 IEEE International
31 March-2 April 1998 Page(s):214 - 219
[AbstractPlus](#) | Full Text: [PDF\(808 KB\)](#) IEEE CNF

- ☐ **13. Impact of intermetal dielectric process on Al via electromigration reliability**
Liu, X.; Lo, K.F.; Chin, K.Y.; Guo, Q.; Teh, G.L.;
Physical and Failure Analysis of Integrated Circuits, 1999. Proceedings of the 1999 7th Internatic
Symposium on the
5-9 July 1999 Page(s):60 - 63
[AbstractPlus](#) | Full Text: [PDF\(368 KB\)](#) IEEE CNF

- ☐ **14. Evaluation of test methods and associated test structures for interconnect reliability control**
Foley, S.; Molyneaux, J.; Mathewson, A.;
Microelectronic Test Structures, 1999. ICMTS 1999. Proceedings of the 1999 International Conf
on
15-18 March 1999 Page(s):167 - 172
[AbstractPlus](#) | Full Text: [PDF\(552 KB\)](#) IEEE CNF

- ☐ **15. Optimized test circuits for SER characterization of a manufacturing process**
Hazucha, P.; Svensson, C.;
Solid-State Circuits, IEEE Journal of
Volume 35, Issue 2, Feb. 2000 Page(s):142 - 148
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(176 KB\)](#) IEEE JNL

- ☐ **16. Instrumentation effects on the detection of resistance transients during accelerated testing of VLSI interconnects**
Fahrenkrug, C.C.F.; Head, L.M.;
Instrumentation and Measurement, IEEE Transactions on
Volume 49, Issue 4, Aug. 2000 Page(s):716 - 720
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(92 KB) IEEE JNL
- ☐ **17. Investigation of Solder Fatigue Acceleration Factors**
Fox, L.; Sofia, J.; Shine, M.;
Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [see also IEEE Transactions on Components, Packaging, and Manufacturing Technology, Part A, B, C]
Volume 8, Issue 2, Jun 1985 Page(s):275 - 282
[AbstractPlus](#) | Full Text: [PDF](#)(1080 KB) IEEE JNL
- ☐ **18. Stress relief in plastic-encapsulated, integrated circuit devices by die coating with photodefinable polyimide**
Khan, M.M.; Tarter, T.S.; Fatemi, H.;
Electronics Components Conference, 1988., Proceedings of the 38th
9-11 May 1988 Page(s):425 - 431
[AbstractPlus](#) | Full Text: [PDF](#)(492 KB) IEEE CNF
- ☐ **19. Moisture sensitivity characterization of plastic surface mount devices using scanning acoustic microscopy**
Shook, R.L.;
Reliability Physics Symposium 1992. 30th Annual Proceedings., International
31 March-2 April 1992 Page(s):157 - 168
[AbstractPlus](#) | Full Text: [PDF](#)(940 KB) IEEE CNF
- ☐ **20. Production implementation of a practical WLR program**
Garrard, S.;
Integrated Reliability Workshop, 1994. Final Report., 1994 International
16-19 Oct. 1994 Page(s):20 - 29
[AbstractPlus](#) | Full Text: [PDF](#)(648 KB) IEEE CNF
- ☐ **21. Reliability assessment of compression contacts for socketable components**
Nagel, A.R.; Gonzalez, C.; Frutsky, K.;
Electrical Contacts, 2000. Proceedings of the Forty-Sixth IEEE Holm Conference on
25-27 Sept. 2000 Page(s):36 - 46
[AbstractPlus](#) | Full Text: [PDF](#)(864 KB) IEEE CNF
- ☐ **22. Experimental comparison of wafer level reliability (WLR) and packaged electromigration test results**
Ryu, C.; Tse-Lun Tsai; Rogers, A.; Jesse, C.; Brozek, T.; Zarr, D.; Adamson, M.; Nayak, S.; Wall
Reliability Physics Symposium, 2001. Proceedings. 39th Annual. 2001 IEEE International
30 April-3 May 2001 Page(s):189 - 193
[AbstractPlus](#) | Full Text: [PDF](#)(564 KB) IEEE CNF
- ☐ **23. Comparison of isothermal, constant current and SWEAT wafer level EM testing methods**
Lee, T.C.; Tibel, D.; Sullivan, T.D.; Forhan, S.;
Reliability Physics Symposium, 2001. Proceedings. 39th Annual. 2001 IEEE International
30 April-3 May 2001 Page(s):172 - 183
[AbstractPlus](#) | Full Text: [PDF](#)(980 KB) IEEE CNF
- ☐ **24. Comparative analysis of low dose-rate, accelerated, and standard cobalt-60 radiation response data for a low-dropout voltage regulator and a voltage reference**
Abare, W.; Brueggeman, F.; Pease, R.; Krieg, J.; Simons, M.;
Radiation Effects Data Workshop, 2002 IEEE
15-19 July 2002 Page(s):177 - 180
[AbstractPlus](#) | Full Text: [PDF](#)(361 KB) IEEE CNF

- ☐ **25. Isothermal em as highly accelerated test method for copper damascene lines**
Kin Leong; Yap Andrew; Bee Hoon Lim; Eng Chye Chua; Yeow Kheng Lim; Suat Cheng; Khoo S
Physical and Failure Analysis of Integrated Circuits, 2002. IPFA 2002. Proceedings of the 9th
International Symposium on the
8-12 July 2002 Page(s):129 - 134
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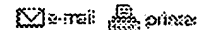
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Design Automation Conference, 1990. Proceedings. 27th ACM/IEEE
24-28 June 1990 Page(s):667 - 672
[AbstractPlus](#) | Full Text: [PDF\(532 KB\)](#) IEEE CNF
- ☐ 2. **Single event gate rupture in thin gate oxides**
Sexton, F.W.; Fleetwood, D.M.; Shaneyfelt, M.R.; Dodd, P.E.; Hash, G.L.;
Nuclear Science, IEEE Transactions on
Volume 44, Issue 6, Dec. 1997 Page(s):2345 - 2352
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(840 KB\)](#) IEEE JNL
- ☐ 3. **SEU simulation and testing of resistor-hardened D-latches in the SA3300 microprocessor**
Sexton, F.W.; Corbett, W.T.; Treece, R.K.; Hass, K.J.; Hughes, K.L.; Axness, C.L.; Hash, G.L.;
Shaneyfelt, M.R.; Wunsch, T.F.;
Nuclear Science, IEEE Transactions on
Volume 38, Issue 6, Dec. 1991 Page(s):1521 - 1528
[AbstractPlus](#) | Full Text: [PDF\(708 KB\)](#) IEEE JNL
- ☐ 4. **SEU characterization and design dependence of the SA3300 microprocessor**
Sexton, F.W.; Treece, R.K.; Hass, K.J.; Hughes, K.L.; Hash, G.L.; Axness, C.L.; Buchner, S.P.; K.;
Nuclear Science, IEEE Transactions on
Volume 37, Issue 6, Dec. 1990 Page(s):1861 - 1868
[AbstractPlus](#) | Full Text: [PDF\(780 KB\)](#) IEEE JNL
- ☐ 5. **Impact of passivation layers on enhanced low-dose-rate sensitivity and pre-irradiation electrical temperature stress effects in bipolar linear ICs**
Shaneyfelt, M.R.; Pease, R.L.; Schwank, J.R.; Maher, M.C.; Hash, G.L.; Fleetwood, D.M.; Dodd, P.E.;
Reber, C.A.; Witczak, S.C.; Riewe, L.C.; Hjalmarson, H.P.; Banks, J.C.; Doyle, B.L.; Knapp, J.A.;
Nuclear Science, IEEE Transactions on
Volume 49, Issue 6, Dec. 2002 Page(s):3171 - 3179
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(436 KB\)](#) IEEE JNL
- ☐ 6. **SEU-sensitive volumes in bulk and SOI SRAMs from first-principles calculations and experiments**
Dodd, P.E.; Shaneyfelt, A.R.; Horn, K.M.; Walsh, D.S.; Hash, G.L.; Hill, T.A.; Draper, B.L.; Schwank, J.R.;
Sexton, F.W.; Winokur, P.S.;
Nuclear Science, IEEE Transactions on
Volume 48, Issue 6, Dec. 2001 Page(s):1893 - 1903

[AbstractPlus](#) | [References](#) | Full Text: [PDF\(360 KB\)](#) IEEE JNL

- ☐ **7. Thermal-stress effects and enhanced low dose rate sensitivity in linear bipolar ICs**
Shaneyfelt, M.R.; Schwank, J.R.; Witczak, S.C.; Fleetwood, D.M.; Pease, R.L.; Winokur, P.S.; Ri
L.C.; Hash, G.L.;
Nuclear Science, IEEE Transactions on
Volume 47, Issue 6, Dec. 2000 Page(s):2539 - 2545
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(124 KB\)](#) IEEE JNL
- ☐ **8. Single-event upset and snapback in silicon-on-insulator devices and integrated circuits**
Dodd, P.E.; Shaneyfelt, M.R.; Walsh, D.S.; Schwank, J.R.; Hash, G.L.; Loemker, R.A.; Draper, B
Winokur, P.S.;
Nuclear Science, IEEE Transactions on
Volume 47, Issue 6, Dec. 2000 Page(s):2165 - 2174
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(161 KB\)](#) IEEE JNL
- ☐ **9. Impact of aging on radiation hardness[CMOS SRAMs]**
Shaneyfelt, M.R.; Winokur, P.S.; Fleetwood, D.M.; Hash, G.L.; Schwank, J.R.; Sexton, F.W.; Pea
R.L.;
Nuclear Science, IEEE Transactions on
Volume 44, Issue 6, Dec. 1997 Page(s):2040 - 2047
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(928 KB\)](#) IEEE JNL
- ☐ **10. The role of thermal and fission neutrons in reactor neutron-induced upsets in commercial
SRAMs**
Griffin, P.J.; Luera, T.F.; Sexton, F.W.; Cooper, P.J.; Karr, S.G.; Hash, G.L.; Fuller, E.;
Nuclear Science, IEEE Transactions on
Volume 44, Issue 6, Dec. 1997 Page(s):2079 - 2086
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(892 KB\)](#) IEEE JNL
- ☐ **11. SEU and SEL response of the Westinghouse 64K E/sup 2/PROM, Analog Devices AD7876
ADC, and the Intel 82527 serial communications controller**
Sexton, F.W.; Hash, G.L.; Connors, M.P.; Murray, J.R.; Schwank, J.R.; Winokur, P.S.; Bradley, E
Radiation Effects Data Workshop, 1994 IEEE
20 July 1994 Page(s):55 - 63
[AbstractPlus](#) | Full Text: [PDF\(708 KB\)](#) IEEE CNF
- ☐ **12. Transient and total dose irradiation of BESOI 4K SRAM**
Hash, G.L.; Schwank, J.R.; Shaneyfelt, M.R.;
Radiation Effects Data Workshop, 1994 IEEE
20 July 1994 Page(s):11 - 14
[AbstractPlus](#) | Full Text: [PDF\(336 KB\)](#) IEEE CNF
- ☐ **13. Correlating defect level to final test fault coverage for modular structured designs
[microcontroller family]**
Powell, T.J.; Butler, K.M.; Ales, M.; Haley, R.; Perry, M.;
VLSI Test Symposium, 1994. Proceedings., 12th IEEE
25-28 April 1994 Page(s):192 - 196
[AbstractPlus](#) | Full Text: [PDF\(372 KB\)](#) IEEE CNF
- ☐ **14. Radiation hardness assurance categories for COTS technologies**
Hash, G.L.; Shaneyfelt, M.R.; Sexton, F.W.; Winokur, P.S.;
Radiation Effects Data Workshop, 1997 IEEE
24 July 1997 Page(s):35 - 40
[AbstractPlus](#) | Full Text: [PDF\(480 KB\)](#) IEEE CNF
- ☐ **15. Neutron-Induced soft errors, latchup, and comparison of SER test methods for SRAM
technologies**
Dodd, P.E.; Shaneyfelt, M.R.; Schwank, J.R.; Hash, G.L.;
Electron Devices Meeting, 2002. IEDM '02. Digest. International



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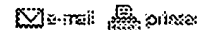
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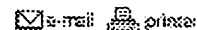
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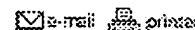
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- ☐ 2. **15th Annual GaAs IC Symposium**
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1993. Technical Digest 1993., 15th A
10-13 Oct. 1993
[AbstractPlus](#) | Full Text: [PDF](#)(80 KB) IEEE CNF
- ☐ 3. **InP integrated circuit technology for microwave, digital, and optoelectronic applications**
Larson, L.E.; Brown, J.J.;
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1992. Technical Digest 1992., 14th A
IEEE
4-7 Oct. 1992 Page(s):247 - 250
[AbstractPlus](#) | Full Text: [PDF](#)(340 KB) IEEE CNF
- ☐ 4. **Experimental 10 Gbit/s transmission systems and its IC technology**
Hagimoto, K.;
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1993. Technical Digest 1993., 15th A
10-13 Oct. 1993 Page(s):7 - 10
[AbstractPlus](#) | Full Text: [PDF](#)(412 KB) IEEE CNF
- ☐ 5. **400 Mbit/s Optical Regenerator Integrated Circuits**
Yamaguchi, K.; Kitasagami, H.; Motegi, M.; Ogawa, F.; Nishimoto, H.; Iwamoto, H.; Kokado, M.
Selected Areas in Communications, IEEE Journal on
Volume 4, Issue 1, Jan 1986 Page(s):184 - 191
[AbstractPlus](#) | Full Text: [PDF](#)(968 KB) IEEE JNL
- ☐ 6. **13th Annual GaAs IC Symposium Technical Digest 1991 (Cat. No.91CH3059-3)**
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1991. Technical Digest 1991., 13th A
20-23 Oct. 1991
[AbstractPlus](#) | Full Text: [PDF](#)(24 KB) IEEE CNF
- ☐ 7. **Realistic fault analysis of CMOS analog building blocks**
Nicolau, P.; Barbosa, J.; Saraiva, M.; Santos, M.B.; Teixeira, I.M.; Teixeira, J.P.;
Defect and Fault Tolerance in VLSI Systems, 1993., The IEEE International Workshop on
27-29 Oct. 1993 Page(s):311 - 318
[AbstractPlus](#) | Full Text: [PDF](#)(388 KB) IEEE CNF

- ☐ **8. Proceedings of CICC 97 - Custom Integrated Circuits Conference**
Custom Integrated Circuits Conference, 1997., Proceedings of the IEEE 1997
5-8 May 1997
[AbstractPlus](#) | Full Text: [PDF](#)(560 KB) IEEE CNF

- ☐ **9. GaAs IC Symposium. 14th Annual IEEE Gallium Arsenide Integrated Circuit Symposium Technical Digest (Cat. No.92CH3197-1)**
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1992. Technical Digest 1992., 14th A
IEEE
4-7 Oct. 1992
[AbstractPlus](#) | Full Text: [PDF](#)(20 KB) IEEE CNF

- ☐ **10. On the analysis of routing, cells and adjacency faults in CMOS digital circuits**
Casimiro, A.P.; Santos, M.B.; Goncalves, F.; Teixeira, J.P.;
Defect and Fault Tolerance in VLSI Systems, 1994. Proceedings., The IEEE International Works
17-19 Oct. 1994 Page(s):263 - 270
[AbstractPlus](#) | Full Text: [PDF](#)(488 KB) IEEE CNF

- ☐ **11. GaAs IC Symposium. IEEE Gallium Arsenide Integrate Circuit Symposium. 24th Annual Te Digest 2002 (Cat. No.02CH37354)**
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 2002. 24th Annual Technical Digest
20-23 Oct. 2002
[AbstractPlus](#) | Full Text: [PDF](#)(608 KB) IEEE CNF

- ☐ **12. IEE Colloquium on 'Power Integrated Circuits' (Digest No.34)**
Power Integrated Circuits, IEE Colloquium on
7 Mar 1989
[AbstractPlus](#) | Full Text: [PDF](#)(16 KB) IEE CNF

- ☐ **13. Technology and reliability issues of multilevel interconnects in bipolar, BiCMOS and CMO VLSIC/ULSICs**
Saxena, A.N.; Ramkumar, K.; Ghosh, S.K.; Bourgeois, M.A.;
Bipolar/BiCOMS Circuits and Technology Meeting, 1993., Proceedings of the 1993
4-5 Oct. 1993 Page(s):12 - 19
[AbstractPlus](#) | Full Text: [PDF](#)(856 KB) IEEE CNF

- ☐ **14. Successful high volume GaAs IC manufacturing the Anadigics experience**
Khetan, S.; Wallace, P.;
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1993. Technical Digest 1993., 15th A
10-13 Oct. 1993 Page(s):119 - 121
[AbstractPlus](#) | Full Text: [PDF](#)(288 KB) IEEE CNF

- ☐ **15. GaAs Integrated circuit fabrication at Motorola**
O'Neil, P.; Bernhardt, B.; Nikpourian, F.; Della, C.; Abad, Y.; Hansell, G.;
Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1993. Technical Digest 1993., 15th A
10-13 Oct. 1993 Page(s):123 - 126
[AbstractPlus](#) | Full Text: [PDF](#)(408 KB) IEEE CNF

- ☐ **16. A novel millimeter-wave IC on Si substrate using flip-chip bonding technology**
Sakai, H.; Ota, Y.; Inoue, K.; Yoshida, T.; Takahashi, K.; Fujita, S.; Sagawa, M.;
Microwave Symposium Digest, 1994., IEEE MTT-S International
23-27 May 1994 Page(s):1763 - 1766 vol.3
[AbstractPlus](#) | Full Text: [PDF](#)(372 KB) IEEE CNF

- ☐ **17. 2001 6th International Conference on Solid-State and Integrated Circuit Technology. Proci (Cat. No.01EX443)**
Solid-State and Integrated-Circuit Technology, 2001. Proceedings. 6th International Conference
Volume 1, 22-25 Oct. 2001
[AbstractPlus](#) | Full Text: [PDF](#)(1222 KB) IEEE CNF

- ☐ **18. The boundary scan**
Burgess, R., Jr.; Nagaraj, P.; Waseq, M.N.;
Potentials, IEEE
Volume 14, Issue 3, Aug.-Sept. 1995 Page(s):11 - 12
[AbstractPlus](#) | Full Text: [PDF\(268 KB\)](#) IEEE JNL
- ☐ **19. Assessment of digital integrated circuit electromagnetic emission based on radiated power evaluation**
Fiori, F.; Pignari, S.;
Electromagnetic Compatibility, IEEE Transactions on
Volume 43, Issue 4, Nov. 2001 Page(s):531 - 537
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(170 KB\)](#) IEEE JNL
- ☐ **20. A preamplifier-shaper-stretcher integrated circuit system for use with germanium strip detectors**
Jagdish, U.; Britton, C.L., Jr.; Ericson, M.N.; Bryan, W.L.; Schwarz, W.G.; Read, M.E.; Kroeger, F.
Nuclear Science, IEEE Transactions on
Volume 47, Issue 6, Dec 2000 Page(s):1868 - 1871
[AbstractPlus](#) | Full Text: [PDF\(272 KB\)](#) IEEE JNL
- ☐ **21. Statistical approach for improving manufacturing yield in advanced IC fabrication**
Carlson, A.C.; Sundaran, S.L.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1991. ASMC 91 Proceedings
IEEE/SEMI 1991
21-23 Oct. 1991 Page(s):25 - 29
[AbstractPlus](#) | Full Text: [PDF\(364 KB\)](#) IEEE CNF
- ☐ **22. Recent advances in power integrated circuits with high level integration**
Robb, S.P.; Sutor, J.L.;
Power Semiconductor Devices and ICs, 1994. ISPSD '94. Proceedings of the 6th International
Symposium on
31 May-2 June 1994 Page(s):343 - 348
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- ☐ **23. Proceedings of IEEE Custom Integrated Circuits Conference - CICC '94**
Custom Integrated Circuits Conference, 1994., Proceedings of the IEEE 1994
1-4 May 1994
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Custom Integrated Circuits Conference, 1995., Proceedings of the IEEE 1995
1-4 May 1995
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- ☐ **25. Reliability of InP-based HBT IC technology for high-speed, low-power applications**
Hafizi, M.; Stanchina, W.E.; Williams, F., Jr.; Jensen, J.F.;
Microwave and Millimeter-Wave Monolithic Circuits Symposium, 1995. Digest of Papers., IEEE 1995
15-16 May 1995 Page(s):111 - 114
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